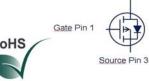


SIPMOS® Small-Signal-Transistor

Features

- P-Channel
- Enhancement mode
- Avalanche rated
- dv/dt rated
- Pb-free lead plating; RoHS compliant
- Qualified according to AEC Q101
- Halogen-free according to IEC61249-2-21



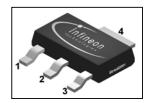


Product Summary

Drain Pin 2, 4

V _{DS}	-60	V
R _{DS(on),max}	0.3	Ω
ID	-1.9	Α

PG-SOT223



Туре	Package	Tape and reel information	Marking	Lead free	Packing
BSP170P	PG-SOT223	H6327: 1000pcs/reel	BSP170P	Yes	Non Dry

Maximum ratings, at T_j =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit	
			steady state		
Continuous drain current	I _D	T _A =25 °C	-1.9	А	
		T _A =70 °C	-1.5		
Pulsed drain current	I _{D,pulse}	T _A =25 °C	-7.6		
Avalanche energy, single pulse	E _{AS}	$I_{\rm D}$ =1.9 A, $R_{\rm GS}$ =25 Ω	70	mJ	
Avalanche energy, periodic limited by $T_{j\max}$	E _{AR}		0.18		
Reverse diode dv/dt	dv/dt	I _D =1.9 A, V _{DS} =48 V, di/dt=-200 A/μs, T _{j,max} =150 °C	-6	kV/μs	
Gate source voltage	V_{GS}		±20	V	
Power dissipation	P _{tot}	T _A =25 °C	1.8	W	
Operating and storage temperature	$T_{\rm j}$, $T_{\rm stg}$		-55 150	°C	
ESD class		JESD22-C101 (HBM)	1A (250V to 500V)		
Soldering temperature			260 °C		
IEC climatic category; DIN IEC 68-1			55/150/56		



Parameter	Symbol	Conditions	Values		Unit	
			min.	typ.	max.	
Thermal characteristics						
Thermal resistance, junction -soldering point	R thJS		-	-	20	K/W
SMD version, device on PCB:	R _{thJA}	minimal footprint	-	-	110	K/W
		6 cm ² cooling area ¹⁾	-	-	70	

Electrical characteristics, at $T_{\rm j}$ =25 °C, unless otherwise specified

Static characteristics

Drain-source breakdown voltage	V _{(BR)DSS}	V _{GS} =0 V, I _D =-250 μA	-60	-	-	V
Gate threshold voltage	$V_{GS(th)}$	V _{DS} =V _{GS} , I _D =-250 μA	-2.1	-3	-4	
Zero gate voltage drain current	I _{DSS}	V _{DS} =-60 V, V _{GS} =0 V, T _j =25 °C	1	-0.1	-1	μΑ
		V _{DS} =-60 V, V _{GS} =0 V, T _j =125 °C	1	-10	-100	
Gate-source leakage current	I _{GSS}	V _{GS} =-20 V, V _{DS} =0 V	-	-10	-100	nA
Drain-source on-state resistance	R _{DS(on)}	V _{GS} =-10 V, I _D =-1.9 A	1	239	300	mΩ
Transconductance	g _{fs}	$ V_{\rm DS} > 2 I_{\rm D} R_{\rm DS(on)max},$ $I_{\rm D} = -1.9 \text{ A}$	1.3	2.6	-	s

¹⁾ Device on 40mm*40mm*1.5 epoxy PCB FR4 with 6cm² (one layer, 70μm thick) copper area for drain connection. PCB is vertical without blown air.



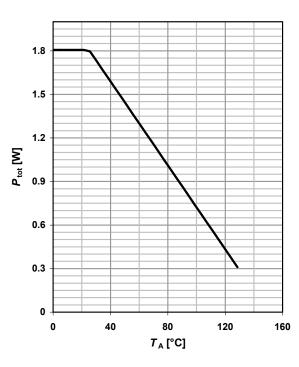
Parameter	Symbol Conditions	Conditions		Values		Unit
			min.	typ.	max.	
Dynamic characteristics						
Input capacitance	C iss		-	328	410	pF
Output capacitance	C oss	V _{GS} =0 V, V _{DS} =-25 V, f=1 MHz	1	105	135	
Reverse transfer capacitance	C rss		1	38	48	
Turn-on delay time	t _{d(on)}		-	14	21	ns
Rise time	t _r	V _{DD} =-30 V, V _{GS} =- 10 V, I _D =-1.9 A,	1	28	42	
Turn-off delay time	t _{d(off)}	$R_{\rm G}=6 \Omega$	-	92	138	
Fall time	t _f		-	60	90	
Gate Charge Characteristics						
Gate to source charge	Q _{gs}		-	-1.4	-1.9	nC
Gate to drain charge	Q _{gd}	$V_{\rm DD}$ =-48 V, $I_{\rm D}$ =-1.9 A, $V_{\rm GS}$ =0 to -10 V	-	-4.9	-7.4	1
Gate charge total	Q _g		-	-10	-14	
Gate plateau voltage	V _{plateau}		-	-4.34	-	V
Reverse Diode						
Diode continuous forward current	Is		_	-	-1.98	Α
Diode pulse current	I _{S,pulse}		-	-	-7.6	
Diode forward voltage	V _{SD}	$V_{\rm GS}$ =0 V, $I_{\rm F}$ =-1.9 A, $T_{\rm j}$ =25 °C	-	-0.83	-1.1	V
Reverse recovery time	t _{rr}	V_R =30 V, I_F = $ I_S $, di_F/dt =100 A/ μ s	-	36	54	ns
Reverse recovery charge	Q _{rr}		-	41	62	nC

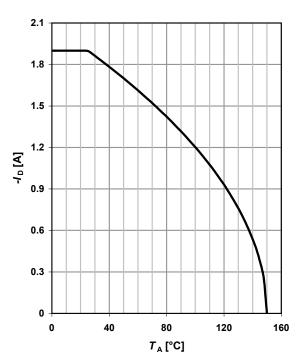


1 Power dissipation

P_{tot} =f(T_{A})

2 Drain current

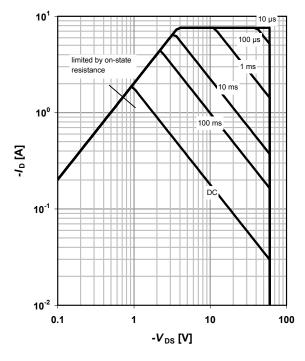




3 Safe operating area

$$I_D = f(V_{DS}); T_A = 25 \text{ °C}^{1)}; D = 0$$

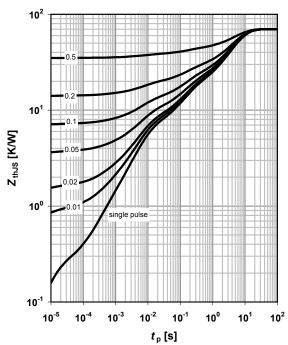
parameter: $t_{\rm p}$



4 Max. transient thermal impedance

$$Z_{thJA}$$
=f(t_p)

parameter: $D = t_p/T$





5 Typ. output characteristics

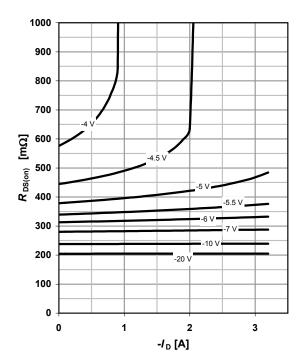
 $I_D = f(V_{DS}); T_j = 25 °C$

parameter: $V_{\rm GS}$

6 Typ. drain-source on resistance

 $R_{DS(on)}$ =f(I_D); T_j =25 °C

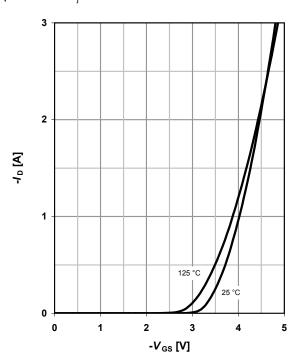
parameter: $V_{\rm GS}$



7 Typ. transfer characteristics

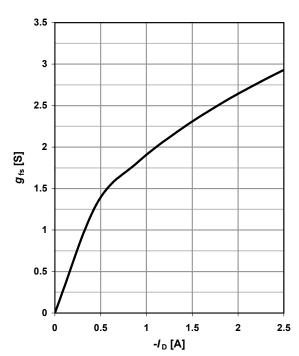
 I_{D} =f(V_{GS}); $|V_{DS}|$ >2 $|I_{D}|R_{DS(on)max}$

parameter: $T_{\rm j}$



8 Typ. forward transconductance

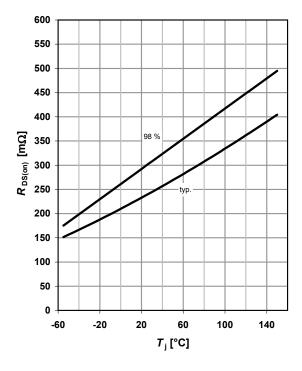
 g_{fs} =f(I_D); T_j =25 °C





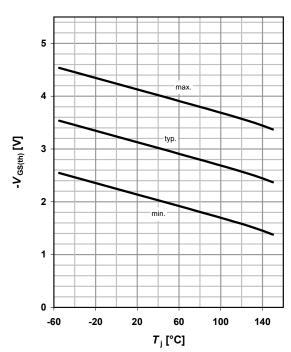
9 Drain-source on-state resistance

$$R_{DS(on)}$$
=f(T_j); I_D =-1.9 A; V_{GS} =-10 V



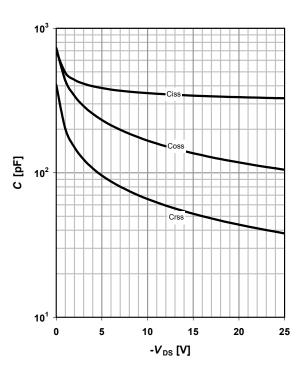
10 Typ. gate threshold voltage

$$V_{GS(th)}$$
=f(T_j); V_{GS} = V_{DS} ; I_D =-250 μ A



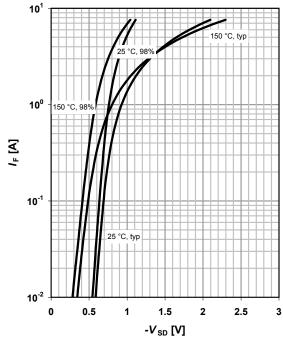
11 Typ. capacitances

$$C = f(V_{DS}); V_{GS} = 0 V; f = 1 MHz$$



12 Forward characteristics of reverse diode

$$I_{F}$$
=f(V_{SD})
parameter: T_{j}

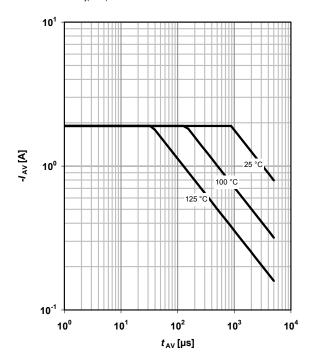




13 Avalanche characteristics

 I_{AS} =f(t_{AV}); R_{GS} =25 Ω

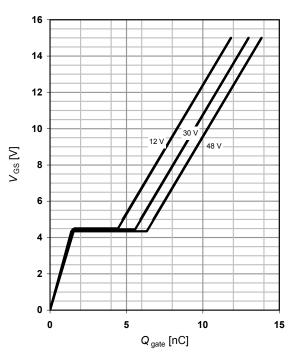
parameter: $T_{j(start)}$



14 Typ. gate charge

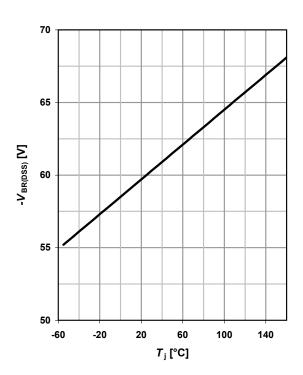
 $V_{\rm GS}$ =f(Q _{gate}); $I_{\rm D}$ =-1.9 A pulsed

parameter: $V_{\rm DD}$



15 Drain-source breakdown voltage

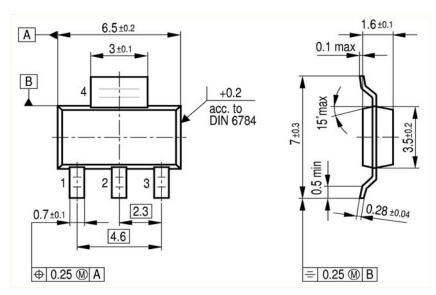
$$V_{BR(DSS)}$$
=f(T_j); I_D =-250 μ A



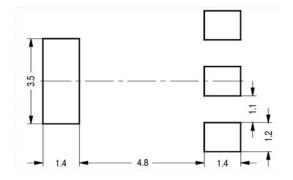


Package Outline

SOT-223: Outline

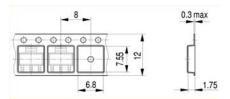


Footprint



Packaging

Tape





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